54F/74F545 Octal Bidirectional Transceiver with TRI-STATE® Outputs

General Description

The 'F545 is an 8-bit, TRI-STATE, high-speed transceiver. It provides bidirectional drive for bus-oriented microprocessor and digital communications systems. Straight through bidirectional transceivers are featured, with 24 mA (20 mA Mil) bus drive capability on the A ports and 64 mA (48 mA Mil) bus drive capability on the B ports.

One input, Transmit/Receive (T/\overline{R}) determines the direction of logic signals through the bidirectional transceiver. Transmit enables data from A ports to B ports; Receive enables data from B ports to A ports. The Output Enable input disables both A and B ports by placing them in a TRI-STATE condition.

Features

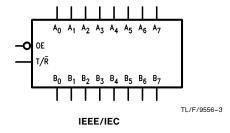
- Higher drive than 8304
- 8-bit bidirectional data flow reduces system package
- TRI-STATE inputs/outputs for interfacing with bus-oriented systems
- 24 mA (20 mA Mil) and 64 mA (48 mA Mil) bus drive capability on A and B ports, respectively
- Transmit/Receive and Output Enable simplify control logic
- Guaranteed 4000V minimum ESD protection
- Pin for Pin compatible with Intel 8286

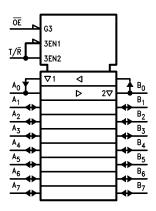
Commercial	Military	Package Number	Package Description			
74F545PC		N20A	20-Lead (0.300" Wide) Molded Dual-In-Line			
	54F545DM (Note 2)	J20A	20-Lead Ceramic Dual-In-Line			
74F545SC (Note 1)		M20B	20-Lead (0.300" Wide) Molded Small Outline, JEDEC			
74F545SJ (Note 1)		M20D	20-Lead (0.300" Wide) Molded Small Outline, EIAJ			
	54F545FM (Note 2)	W20A	20-Lead Cerpack			
	54F545LM (Note 2)	E20A	20-Lead Ceramic Leadless Chip Carrier, Type C			

Note 1: Devices also available in 13" reel. Use suffix = SCX and SJX.

 $\textbf{Note 2:} \ \textbf{Military grade device with environmental and burn-in processing.} \ \textbf{Use suffix} = \textbf{DMQB, FMQB and LMQB.}$

Logic Symbols



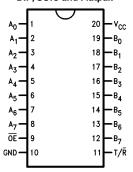


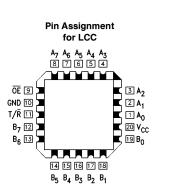
TL/F/9556-5

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Connection Diagrams

Pin Assignment for DIP, SOIC and Flatpak





TL/F/9556-2

TL/F/9556-1

Truth Table

Inputs		Outputs				
ŌĒ	T/R	Outputs				
L	L	Bus B Data to Bus A				
L	Н	Bus A Data to Bus B				
Н	X	High Z				

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Immaterial
 Z = High Impedance

Unit Loading/Fan Out

		54F/74F				
Pin Names	Description	U.L. HIGH/LOW	Input I _{IH} /I _{IL} Output I _{OH} /I _{OL}			
ŌĒ	Output Enable Input (Active LOW)	1.0/2.0	20 μA/ – 1.2 mA			
T/R	Transmit/Receive Input	1.0/2.0	20 μA/ – 1.2 mA			
A ₀ -A ₇	Side A TRI-STATE Inputs or	3.5/1.083	70 μΑ/ – 650 μΑ			
	TRI-STATE Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)			
B ₀ -B ₇	Side B TRI-STATE Inputs or	3.5/1.083	70 μΑ/ – 650 μΑ			
	TRI-STATE Outputs	600/106.6 (80)	-12 mA/64 mA (48 mA)			

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C Junction Temperature under Bias -55°C to +175°C Plastic -55°C to +150°C

V_{CC} Pin Potential to

Ground Pin -0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0V

Input Current (Note 2) -30~mA to +5.0~mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to $V_{\mbox{\footnotesize CC}}$ TRI-STATE Output -0.5V to +5.5V

Current Applied to Output in LOW State (Max) ESD Last Passing Voltage (Min)

twice the rated I_{OL} (mA) 4000V be damaged or have its useful life impaired. Functional operation under these conditions is not implied. Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Note 1: Absolute maximum ratings are values beyond which the device may

Recommended Operating Conditions

Free Air Ambient Temperature

Military -55°C to +125°C 0°C to $\,\pm\,70^{\circ}\text{C}$ Commercial

Supply Voltage

 $+\,4.5V$ to $+\,5.5V$ Military Commercial +4.5V to +5.5V

DC Electrical Characteristics

Symbol	Parameter -		54F/74F			Units	Vcc	Conditions	
Symbol			Min	Тур	Max	Units	vcc vcc	Conditions	
V _{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal		
V _{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal		
V _{CD}	Input Clamp Diode Vo	oltage			-1.2	V	Min	$I_{IN} = -18 \text{ mA } (\overline{OE}, T/\overline{R})$	
V _{OH}	Output HIGH Voltage	54F 10% V _{CC} 54F 10% V _{CC} 54F 10% V _{CC} 74F 10% V _{CC} 74F 10% V _{CC} 74F 10% V _{CC} 74F 5% V _{CC} 74F 5% V _{CC}	2.5 2.4 2.0 2.5 2.4 2.0 2.7 2.7			V	Min	$\begin{split} I_{OH} &= -1 \text{ mA } (A_n) \\ I_{OH} &= -3 \text{ mA } (A_n) \\ I_{OH} &= -12 \text{ mA } (B_n) \\ I_{OH} &= -11 \text{ mA } (A_n) \\ I_{OH} &= -3 \text{ mA } (A_n) \\ I_{OH} &= -15 \text{ mA } (B_n) \\ I_{OH} &= -1 \text{ mA } (A_n) \\ I_{OH} &= -3 \text{ mA } (A_n) \\ I_{OH} &= -3 \text{ mA } (A_n) \end{split}$	
V _{OL}	Output LOW Voltage	54F 10% V _{CC} 54F 10% V _{CC} 74F 10% V _{CC} 74F 10% V _{CC}			0.5 0.55 0.5 0.55	٧	Min	$I_{OL} = 20 \text{ mA } (A_n)$ $I_{OL} = 48 \text{ mA } (B_n)$ $I_{OL} = 24 \text{ mA } (A_n)$ $I_{OL} = 64 \text{ mA } (B_n)$	
I _{IH}	Input HIGH Current	54F 74F			20.0 5.0	μΑ	Max	$V_{IN} = 2.7V (\overline{OE}, T/\overline{R})$	
I _{BVI}	Input HIGH Current Breakdown Test	54F 74F			100 7.0	μΑ	Max	$V_{IN} = 7.0V (\overline{OE}, T/\overline{R})$	
I _{BVIT}	Input HIGH Current Breakdown (I/O)	54F 74F			1.0 0.5	mA	Max	$V_{IN} = 5.5V (A_n, B_n)$	
I _{CEX}	Output HIGH Leakage Current	54F 74F			250 50	μΑ	Max	$V_{OUT} = V_{CC}$	
V_{ID}	Input Leakage Test	74F	4.75			V	0.0	$I_{\text{ID}} = 1.9 \mu\text{A}$ All Other Pins Grounded	
I _{OD}	Output Leakage Circuit Current	74F			3.75	μΑ	0.0	V _{IOD} = 150 mV All Other Pins Grounded	
I _{IL}	Input LOW Current				-1.2	mA	Max	$V_{IN} = 0.5V (\overline{OE}, T/\overline{R})$	
I _{IH} + I _{OZH}	Output Leakage Current				70	μΑ	Max	$V_{OUT} = 2.7V (A_n, B_n)$	
I _{IL} + I _{OZL}	Output Leakage Current				-650	μΑ	Max	$V_{OUT} = 0.5V (A_n, B_n)$	
los	Output Short-Circuit (-60 -100		150 225	mA	Max	$V_{OUT} = 0V (A_n)$ $V_{OUT} = 0V (B_n)$		

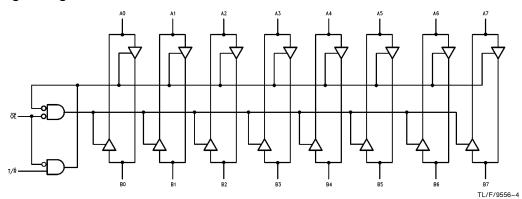
DC Electrical Characteristics (Continued)

Symbol	Parameter		54F/74F		Units	V _{CC}	Conditions	
	Farameter	Min	Тур	Max	Office	▼ CC		
I _{ZZ}	Bus Drainage Test			500	μΑ	0.0V	$V_{OUT} = 5.25V$	
I _{CCH}	Power Supply Current		70	90	mA	Max	V _O = HIGH	
I _{CCL}	Power Supply Current		95	120	mA	Max	$V_O = LOW$	
I _{CCZ}	Power Supply Current		85	110	mA	Max	V _O = HIGH Z	

AC Electrical Characteristics

					54F T _A , V _{CC} = Mil C _L = 50 pF		74F T _A , V _{CC} = Com C _L = 50 pF		Units
Symbol	Parameter								
		Min	Тур	Max	Min	Max	Min	Max	
t _{PLH}	Propagation Delay	2.5	4.2	6.0	2.0	7.5	2.5	7.0	ns
t _{PHL}	A_n to B_n or B_n to A_n	2.5	4.6	6.0	2.0	7.5	2.5	7.0	113
t _{PZH}	Output Enable Time	3.0	5.3	7.0	2.5	9.0	3.0	8.0	
t _{PZL}		3.5	6.0	8.0	3.0	10.0	3.5	9.0	ns
t _{PHZ}	Output Disable Time	3.0	5.0	6.5	2.5	9.0	3.0	7.5	"
t _{PLZ}		2.0	5.0	6.5	2.0	10.0	2.0	7.5	

Logic Diagram

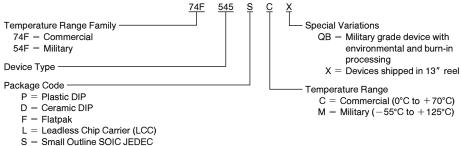


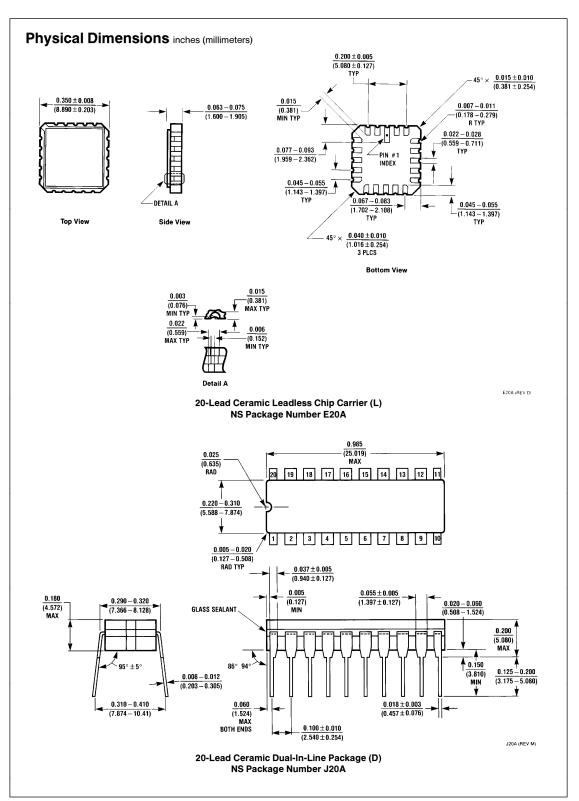
Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

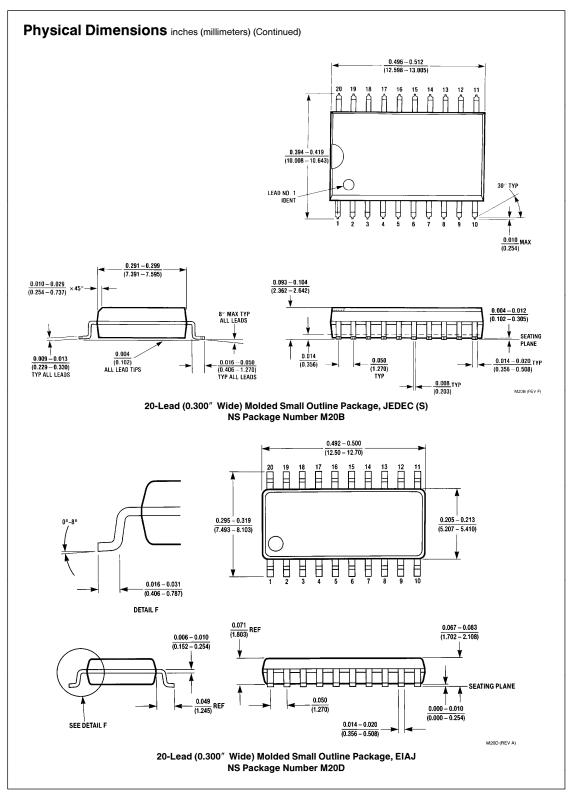
Ordering Information

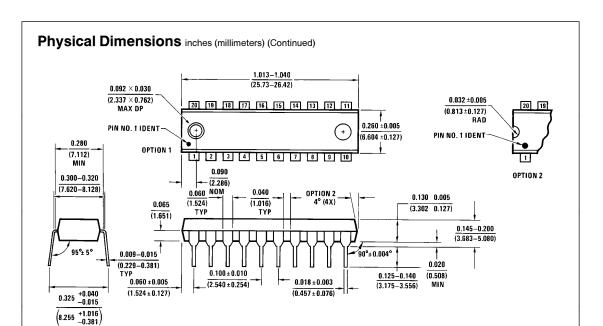
SJ = Small Outline SOIC EIAJ

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:



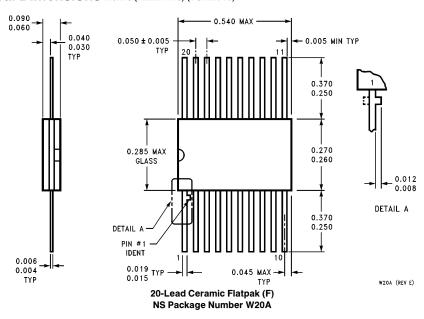






20-Lead (0.300" Wide) Molded Dual-In-Line Package (P) NS Package Number N20A N20A (REV G)

Physical Dimensions inches (millimeters) (Continued)



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National Semiconductor National Semiconducto Corporation 1111 West Bardin Road Arlington, TX 76017 Tel: 1(800) 272-9959 Fax: 1(800) 737-7018

National Semiconductor Europe

Fax: (+49) 0-180-530 85 86 Fax: (+49) U-18U-35U oo oo Email: onjwege tevm2.nsc.com Deutsch Tel: (+49) 0-180-530 85 85 English Tei: (+49) 0-180-532 78 32 Français Tei: (+49) 0-180-532 93 58 Italiano Tel: (+49) 0-180-534 16 80

National Semiconductor National Semiconductor Hong Kong Ltd. 13th Floor, Straight Block, Ocean Centre, 5 Canton Rd. Tsimshatsui, Kowloon Hong Kong Tel: (852) 2737-1600 Fax: (852) 2736-9960

National Semiconductor Japan Ltd.
Tel: 81-043-299-2309
Fax: 81-043-299-2408